

ISO 20411:2018-03 (E)

Surface chemical analysis - Secondary ion mass spectrometry - Correction method for saturated intensity in single ion counting dynamic secondary ion mass spectrometry

Contents		Page
Foreword		iv
Introduction		v
1	Scope	1
2	Normative references	1
3	Terms and definitions	1
4	Symbols and abbreviated terms	2
5	Outline of method	3
6	Procedure for evaluating intensity linearity	5
6.1	Obtaining reference sample	5
6.2	Setting the sample	5
6.3	Operating the instrument	5
6.3.1	Setting the ion beam and the mass analyser	5
6.3.2	Setting the charge compensation	5
6.3.3	Setting the ion detector	5
6.4	Acquiring the data	5
6.5	Assessing the linearity without and with intensity correction	6
6.5.1	Interpolating the minor isotope intensity	6
6.5.2	Correcting the ratio of the isotope abundance to the instrument transmittance	7
6.5.3	Assessing the linearity of intensity	8
6.5.4	Correcting the saturated intensity	8
6.5.5	Assessing the uncertainty of the data	11
7	Reporting the results	12
8	Correcting saturated intensity to the measurement results of the analysis samples	12
Annex A (informative)	Effect of the dead time correction with various instruments for VAMAS study	13
Bibliography		15